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Applicant(s)/Patent under Reexamination
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Art Unit

Examiner

Brian E. Miller

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Class	Subclass	Date	Examiner	
360	324			
324	252			
324	207.21			
338	32R,32H	12/1/2004	BEM	

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
360	324	12/1/2004	ВЕМ	
324	252	12/1/2004	BEM	

(INCLUDING SEARCH	SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR		
EAST Search (enclosed)	12/1/2004	BEM		
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